Transistors Panasonic

MSG36D42

SiGe HBT type

For low-noise RF amplifier

■ Features

- Compatible between high breakdown voltage and high cutoff frequency
- Low-noise, high-gain amplification
- Two elements incorporated into one package (Each transistor is separated)
- SSSMini type package, reduction of the mounting area and assembly cost

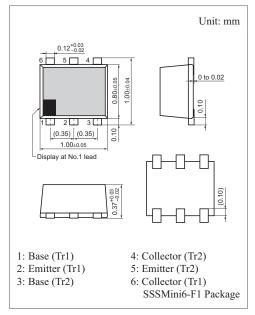
■ Basic Part Number

■ MSG330D4 + MSG33002

■ Absolute Maximum Ratings $T_a = 25$ °C

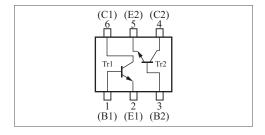
Parameter		Symbol	Rating	Unit	
Trl	Collector-base voltage (Emitter open)	V _{CBO}	9	V	
	Collector-emitter voltage (Base open)	V _{CEO}	6	V	
	Emitter-base voltage (Collector open)	V_{EBO}	1	V	
	Collector current	I_{C}	100	mA	
Tr2	Collector-base voltage (Emitter open)	V _{CBO}	9	V	
	Collector-emitter voltage (Base open)	V _{CEO}	6	V	
	Emitter-base voltage (Collector open)	V _{EBO}	1	V	
	Collector current	I_{C}	60	mA	
Overall	Total power dissipation *	P_{T}	125	mW	
	Junction temperature	T_j	125	°C	
	Storage temperature	T _{stg}	-55 to +125	°C	

Note) Copper plate at the collector is 5.0 mm² on substrate at 10 mm \times 12 mm \times 0.8 mm.



Marking Symbol: 6E

Internal Connection



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■ Electrical Characteristics $T_{\alpha} = 25$ °C±3°C

■ Tr1

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 9 \text{ V}, I_{E} = 0$			1	μА
Collector-emitter cutoff current (Base open)	I_{CEO}	$V_{CH} = 6 \text{ V}, I_{B} = 0$			1	μА
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = 1 \text{ V, } I_{C} = 0$			1	μА
Forward current transfer ratio	h _{FE}	$V_{CE} = 3 \text{ V}, I_{C} = 15 \text{ mA}$	100		220	_
Transition frequency *	f_T	$V_{CH} = 3 \text{ V}, I_{Cl} = 30 \text{ mA}, f = 2 \text{ GHz}$		14		GHz
Forward transfer gain *	S _{21e} 2	$V_{CH} = 3 \text{ V}, I_{Cl} = 30 \text{ mA}, f = 2 \text{ GHz}$	3.0	6.0		dB
Noise figure *	NF	$V_{CH} = 3 \text{ V}, I_{Cl} = 15 \text{ mA}, f = 2 \text{ GHz}$		1.6	2.2	dB
Collector output capacitance (Common base, input open circuited) *	C _{ob}	$V_{CB} = 3 \text{ V}, I_{E} = 0, f = 1 \text{ MHz}$		1.0	1.3	pF

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

- 2. Observe precautions for handling. Electrostatic sensitive devices.
- 3. *: Verified by random sampling

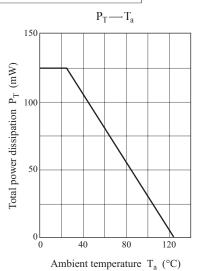
• Tr2

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 9 \text{ V}, I_{E} = 0$			1	μΑ
Collector-emitter cutoff current (Base open)	I _{CEO}	$V_{CH} = 6 \text{ V}, I_{B} = 0$			1	μА
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = 1 \text{ V, } I_{C} = 0$			1	μА
Forward current transfer ratio	h _{FE}	$V_{\rm CH} = 3 \text{ V, } I_{\rm C} = 6 \text{ mA}$	100		220	_
Transition frequency *	f_T	$V_{CH} = 3 \text{ V}, I_{CI} = 20 \text{ mA}, f = 2 \text{ GHz}$		19		GHz
Forward transfer gain *	S _{21e} 2	$V_{CE} = 3 \text{ V}, I_{CI} = 20 \text{ mA}, f = 2 \text{ GHz}$	7.5	10.5		dB
Noise figure *	NF	$V_{CH} = 3 \text{ V}, I_{CI} = 6 \text{ mA}, f = 2 \text{ GHz}$		1.4	2.0	dB
Collector output capacitance (Common base, input open circuited) *	C _{ob}	$V_{CB} = 3 \text{ V}, I_{H} = 0, f = 1 \text{ MHz}$		0.3	0.6	pF

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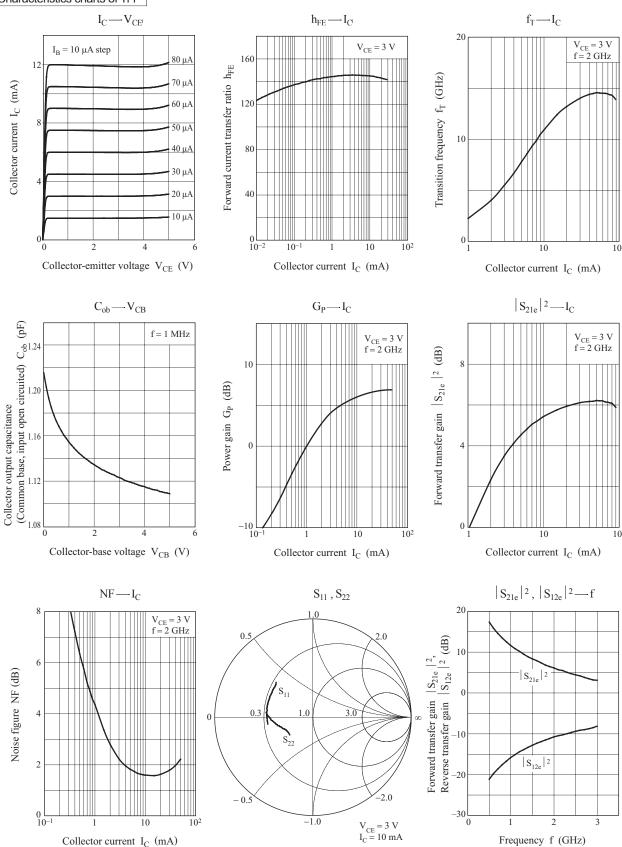
Common characteristics chart



2 SJC00341AED

Panasonic MSG36D42

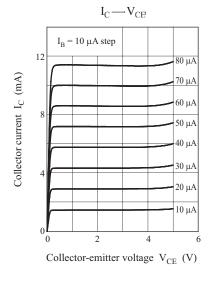
Characteristics charts of Tr1

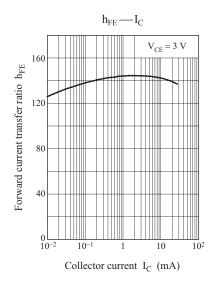


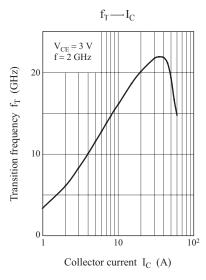
SJC00341AED 3

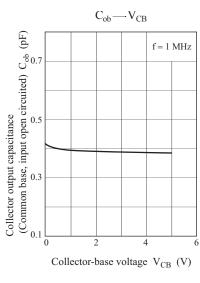
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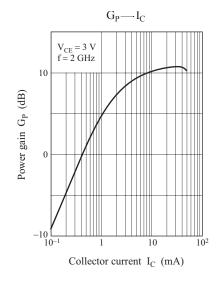
Characteristics charts of Tr2

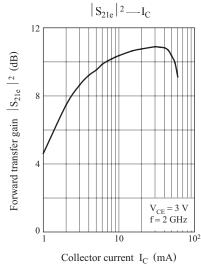


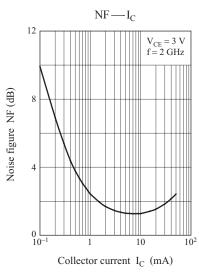


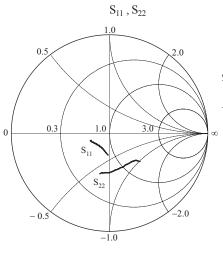


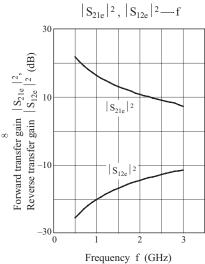












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